# Minji Shon

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## RESEARCH INTERESTS

Circuit Reliability, Analog and Mixed-signal IC design, Digital circuit design, Wafer Level Reliability, Device modeling, characterization, Evaluation and Analysis

6+ years of strong hands-on experience with <u>DFR (Design For Reliability)</u> as reliability engineer' in Quality & Reliability team, Foundry Business, Samsung Electronics

#### **EDUCATION**

Mar. 2012 – Aug. 2016	SOGANG UNIVERSITY	Seoul, Republic of Korea
	B.S., Electronic Engineering	
-	<b>Graduated with Honors</b>	<b>GPA(Major) 3.9/4.0, GPA(Total) 3.84/4.0</b> (1 out of 21, 130 credits)

Jan. 2015 - May. 2015

#### UNIVERSITY of CONNECTICUT

Storrs, CT, USA agineering GPA (Major) 4.0/4.0

Exchange Student, Electrical and Computer Engineering

## WORK EXPERIENCE

Aug. 2016 – Present

**SAMSUNG ELECTRONICS** 

Republic of Korea

Technology Quality & Reliability Engineer

## **Implemented circuit aging environment**

- Built up aging PDK components based on accelerated Si test results up to 3nm GAA technology

# Improved the coverage and accuracy of transistor's aging models

- Implemented aging models including HCI(Hot Carrier Injection), BTI(Bias Temperature Instability) degradation and TDDB(Time Dependent Dielectric Breakdown) ppm calculation on FinFET Technology
- Improved consistency of Model to Hardware Correlation (MHC) with ring oscillators' frequency degradation
- Provide layout-based self-heat models and simulation environments collaborating with device reliability group
- Implemented statistical aging simulation tools to support process variation based on wafer level Si test results

#### Provided IP and product-level reliability verification methods

- Guided aging-aware circuit design methods contributing to Samsung's Exynos devices from 14nm to 4nm technology
- Reviewed HCI body-effect and implemented aging models in simulation environments to support 1.8V and 3.3V GPIO by stacking Single Gate devices for 3nm GAA technology
- Collaborated with a Design Technology group to provide guidance of reliability timing margin for Application Processor devices with critical path aging simulation. Put efforts to provide realistic timing margin analyzing BTI effects
- Provided aging-aware verification methods in real operating conditions: Multi-step aging and Power-Down mode simulation methods causing HCI degradation and aging-induced Vt mismatch in ICs
- Implemented verification methods to support overdrive voltage memory IPs such as eFUSE, OTP and MRAM.

Oct. 2021 – Dec. 2021 SAMSUNG ELECTRONICS

Republic of Korea

Dispatch, Design Enablement Team

- Dispatched to RF device modeling group to enhance RF device reliability in both DC and AC simulation
- Extracted binning and global models for 8nm RF technology

## Jul. 2016 – Aug. 2016 SAMSUNG ELECTRONICS

Republic of Korea

Intern, Technology Quality & Reliability Group

- Proposed enhancing dynamic device voltage check methodology by analyzing bias check simulation environment

## Jan. 2016 – Jun. 2016 SOGANG UNIVERSITY

Republic of Korea

Undergraduate student research, Signal Processing Systems Laboratory

- Implemented real-time high-speed and high-resolution ultrasound image processing in equipment by using CUDA GPU language (Advisor: Taekyung Song)

## **HONORS & AWARDS**

- Dean's List, Sogang University
- Full National Scholarship for Academic Excellence, Korea Student Aid Foundation (KSAF), 2014~2016; 20,000 USD
- Honors Scholarship for Academic Excellence, Sogang University, 2012~2015; 10,000 USD

#### **PUBLICATION**

- Shim, H., Jo, J., Kim, Y., Jeong, B., **Shon, M**., Jiang, H., & Pae, S., Aging-aware design verification methods under real product operating conditions. *In 2019 IEEE International Reliability Physics Symposium (IRPS)*, pp. 1-4, 2019

## **ENGINEERING SKILLS & TOOLS**

- Development of customized reliability simulation tools from Cadence and Synopsys
- Data analysis. Automation script for aging model implementation
  Circuit Netlisting Finesim; Hspice; Spectre

**Reliability Simulation Tools** RelXpert; MOSRA; OMI; Spectre-native

Tool Packages Cadence Virtuoso; MATLAB

High level-languagesPython; CScripting LanguagesPerl; TCL

# TEACHING EXPERIENCE

## SAMSUNG ELECTRONICS Republic of Korea

**Education Mentor** 

Jan. 2020 - Mar. 2020

- Dispatched as a mentor for SVP(Samsung Value Program) mentoring new employees
- Presented lectures of global business manners and etiquettes, also managed time schedules for education programs
- Performed the role of facilitator providing guidance in team projects to bring out members' creativity and abilities

# SAMSUNG ELECTRONICS Republic of Korea

**Education Mentor** 

Jan. 2022 - Mar. 2022

- Dispatched as a sub-course manager for GNEC(Global New Employee Course)
- Presented lectures of communication skills and creative thinking

# SAMSUNG SQUASH CLUB

Republic of Korea

Chief of a Club; Playing Coach

Jan. 2017 – Present

- Held squash competitions for Samsung squash clubs and year-end parties managing club members and finance; Provide lessons

#### LANGUAGE PROFICIENCY

- Proficient in English, Native in Korean
- IBT TOEFL: 102 (Reading: 26, Listening: 29, Speaking: 21, Writing: 26)
- New GRE: 154(Verbal Reasoning)/168(Quantitative Reasoning)/4.0(Analytical Writing)